

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
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NEW APPLICATION

LIST OF REFERENCES CITED BY APPLICANT



APPLICANT

Toshimitsu TETSUI, et al.

FILING DATE

HEREWITH

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,226,985	07-13-93	Y-W. KIM et al.			
	AB	5,558,729	09-24-96	Y-W. KIM, et al.			
	AG	5,442,847	08-22-95	S.L. SEMIATIN, et al.			
	AD	5,846,351	12-08-98	N. MASAHASHI, et al.			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AD	64-042539	02-14-89	JAPAN		X
	AP	1-298127	12-01-89	JAPAN		X
	AD	6-049565	02-22-94	JAPAN		X
	AK	6-041661	02-15-94	JAPAN		X
	AS	62-000215	01-06-87	JAPAN		X
	AT	4-066630	03-03-92	JAPAN		X
	AU	4-124236	04-24-92	JAPAN		X
	AV	6-49624	02-22-94	JAPAN		X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	D. ZHANG et al., Intermetallics, Vol. 7, No. 10, XP-004177382, pps. 1081-1087, "Characterization of Controlled Microstructures in A TIAI (Cr, Mo, Si, B) ALLOY," October 1999.
	AX	"ASM Handbook: Vol. 3 Alloy Phase Diagrams," ASM International, 1992, p. 254.
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.